

**Search Notes**

Application/Control No.

10/810,926

Examiner

Vuthe Siek

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	1,2,11,19- 21	7/31/2006	VS
700	108,112	8/2/2006	VS
700	115	8/2/2006	VS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST ALL DATABASES	7/31/2006	VS
UPDATED SEARCH EAST & IEEE	8/2/2006	VS